

## **MOSFET**

## OptiMOS<sup>™</sup> 5 Power-Transistor, 100 V

### **Features**

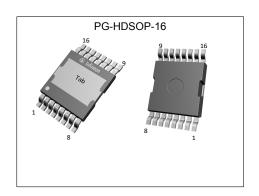
- N-channel
- Very low on-resistance R<sub>DS(on)</sub>
   Superior thermal resistance
- 100% avalanche tested
- Pb-free lead plating; RoHS compliant
  Halogen-free according to IEC61249-2-21

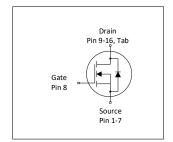
### **Product validation**

Fully qualified according to JEDEC for Industrial Applications

Table 1 **Key Performance Parameters** 

Parameter	Value	Unit
<b>V</b> <sub>DS</sub>	100	V
$R_{\mathrm{DS(on),max}}$	1.4	mΩ
I <sub>D</sub>	365	A
Qoss	213	nC
Q <sub>G</sub>	168	nC











Type / Ordering Code	Package	Marking	Related Links
IPTC014N10NM5	PG-HDSOP-16	14N10NM5	-

# OptiMOS<sup>TM</sup> 5 Power-Transistor, 100 V IPTC014N10NM5



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# OptiMOS<sup>™</sup> 5 Power-Transistor, 100 V IPTC014N10NM5



# 1 Maximum ratings at $T_A$ =25 °C, unless otherwise specified

Table 2 Maximum ratings

Davamatar	Ob. a.l	Values			1114	
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition
Continuous drain current <sup>1)</sup>	I <sub>D</sub>	- - - -	- - -	365 258 216 37	A	$V_{GS}$ =10 V, $T_{C}$ =25 °C $V_{GS}$ =10 V, $T_{C}$ =100 °C $V_{GS}$ =6 V, $T_{C}$ =100 °C $V_{GS}$ =10V, $T_{A}$ =25°C, $R_{thJA}$ =40°C/W <sup>2)</sup>
Pulsed drain current <sup>3)</sup>	I <sub>D,pulse</sub>	-	-	1460	Α	<i>T</i> <sub>A</sub> =25 °C
Avalanche energy, single pulse <sup>4)</sup>	<b>E</b> AS	-	-	775	mJ	$I_D$ =150 A, $R_{GS}$ =25 Ω
Gate source voltage	V <sub>GS</sub>	-20	-	20	V	-
Power dissipation	P <sub>tot</sub>	-	-	375 3.8	W	T <sub>C</sub> =25 °C T <sub>A</sub> =25 °C, R <sub>thJA</sub> =40 °C/W <sup>2)</sup>
Operating and storage temperature	T <sub>j</sub> , T <sub>stg</sub>	-55	-	175	°C	IEC climatic category; DIN IEC 68-1 55/175/56

#### 2 Thermal characteristics

Table 3 **Thermal characteristics** 

Parameter	Symbol	Values			Unit	Note / Test Condition	
Farameter	Symbol	Min.	Тур.	Max.	Ullit	Note / Test Condition	
Thermal resistance, junction - case	R <sub>thJC</sub>	-	0.2	0.4	°C/W	-	
Thermal resistance, junction - ambient, 6 cm² cooling area²)		-	-	40	°C/W	-	
Thermal resistance, junction - ambient, minimal footprint	R <sub>thJA</sub>	-	-	62	°C/W	-	

<sup>&</sup>lt;sup>1)</sup> Rating refers to the product only with datasheet specified absolute maximum values, maintaining case temperature as specified. For other case temperatures please refer to Diagram 2. De-rating will be required based on the actual environmental conditions.  $^{2)}$  Device on 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm $^{2}$  (one layer, 70  $\mu$ m thick) copper area for drain

connection. PCB is vertical in still air.

3) See Diagram 3 for more detailed information

4) See Diagram 13 for more detailed information

# OptiMOS<sup>™</sup> 5 Power-Transistor, 100 V IPTC014N10NM5



# 3 Electrical characteristics at $T_j$ =25 °C, unless otherwise specified

Table 4 **Static characteristics** 

	0	Values				
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition
Drain-source breakdown voltage	V <sub>(BR)DSS</sub>	100	-	-	V	V <sub>GS</sub> =0 V, I <sub>D</sub> =1 mA
Gate threshold voltage	$V_{\rm GS(th)}$	2.2	3.0	3.8	V	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =280 μA
Zero gate voltage drain current	I <sub>DSS</sub>	-	0.1 10	5.0 100	μΑ	V <sub>DS</sub> =100 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =25 °C V <sub>DS</sub> =100 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =125 °C
Gate-source leakage current	I <sub>GSS</sub>	-	10	100	nA	V <sub>GS</sub> =20 V, V <sub>DS</sub> =0 V
Drain-source on-state resistance	R <sub>DS(on)</sub>	-	1.3 1.6	1.4 2.0	mΩ	V <sub>GS</sub> =10 V, I <sub>D</sub> =150 A V <sub>GS</sub> =6 V, I <sub>D</sub> =75 A
Gate resistance <sup>1)</sup>	R <sub>G</sub>	-	1.4	2.1	Ω	-
Transconductance	<b>g</b> fs	140	280	-	S	<i>V</i> <sub>DS</sub>  ≥2  <i>I</i> <sub>D</sub>   <i>R</i> <sub>DS(on)max</sub> , <i>I</i> <sub>D</sub> =100 A

Table 5 **Dynamic characteristics** 

Danamatan	Ob. a.l		Values			N / / T / O   III
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition
Input capacitance <sup>1)</sup>	C <sub>iss</sub>	-	12000	16000	pF	V <sub>GS</sub> =0 V, V <sub>DS</sub> =50 V, f=1 MHz
Output capacitance <sup>1)</sup>	Coss	-	1800	2300	pF	V <sub>GS</sub> =0 V, V <sub>DS</sub> =50 V, f=1 MHz
Reverse transfer capacitance <sup>1)</sup>	C <sub>rss</sub>	-	80	140	pF	V <sub>GS</sub> =0 V, V <sub>DS</sub> =50 V, f=1 MHz
Turn-on delay time	$t_{\sf d(on)}$	-	36	_	ns	$V_{\rm DD}$ =50 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =100 A, $R_{\rm G,ext}$ =1.6 $\Omega$
Rise time	t <sub>r</sub>	-	30	-	ns	$V_{\rm DD}$ =50 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =100 A, $R_{\rm G,ext}$ =1.6 $\Omega$
Turn-off delay time	$t_{ m d(off)}$	-	85	-	ns	$V_{\rm DD}$ =50 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =100 A, $R_{\rm G,ext}$ =1.6 $\Omega$
Fall time	t <sub>f</sub>	-	30	-	ns	$V_{\rm DD}$ =50 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =100 A, $R_{\rm G,ext}$ =1.6 $\Omega$

Gate charge characteristics<sup>2)</sup> Table 6

Parameter	Cumbal	Values			l lmi4	Note / Test Condition
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition
Gate to source charge	$Q_{gs}$	-	53	-	nC	$V_{\rm DD}$ =50 V, $I_{\rm D}$ =100 A, $V_{\rm GS}$ =0 to 10 V
Gate charge at threshold	Q <sub>g(th)</sub>	-	36	-	nC	$V_{DD}$ =50 V, $I_{D}$ =100 A, $V_{GS}$ =0 to 10 V
Gate to drain charge <sup>1)</sup>	<b>Q</b> <sub>gd</sub>	-	34	51	nC	$V_{DD}$ =50 V, $I_{D}$ =100 A, $V_{GS}$ =0 to 10 V
Switching charge	Q <sub>sw</sub>	-	51	-	nC	$V_{DD}$ =50 V, $I_{D}$ =100 A, $V_{GS}$ =0 to 10 V
Gate charge total <sup>1)</sup>	<b>Q</b> g	-	168	211	nC	$V_{DD}$ =50 V, $I_{D}$ =100 A, $V_{GS}$ =0 to 10 V
Gate plateau voltage	V <sub>plateau</sub>	-	4.4	-	V	$V_{DD}$ =50 V, $I_{D}$ =100 A, $V_{GS}$ =0 to 10 V
Output charge <sup>1)</sup>	Qoss	-	213	285	nC	V <sub>DS</sub> =50 V, V <sub>GS</sub> =0 V

 $<sup>^{1)}</sup>$  Defined by design. Not subject to production test.  $^{2)}$  See "Gate charge waveforms" for parameter definition

# OptiMOS<sup>TM</sup> 5 Power-Transistor, 100 V IPTC014N10NM5

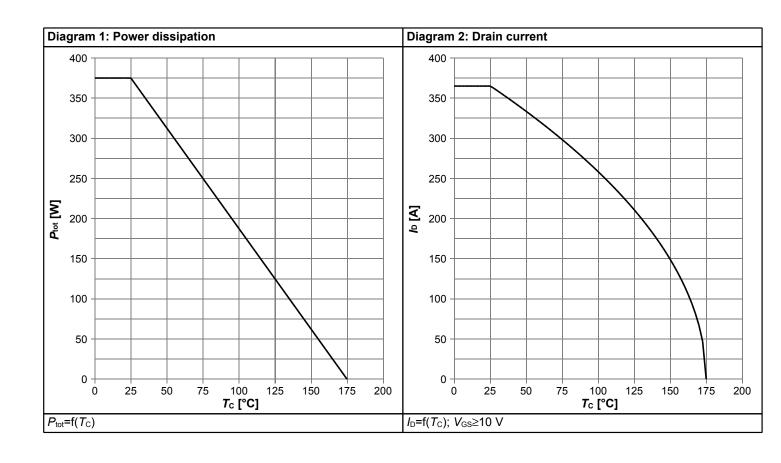


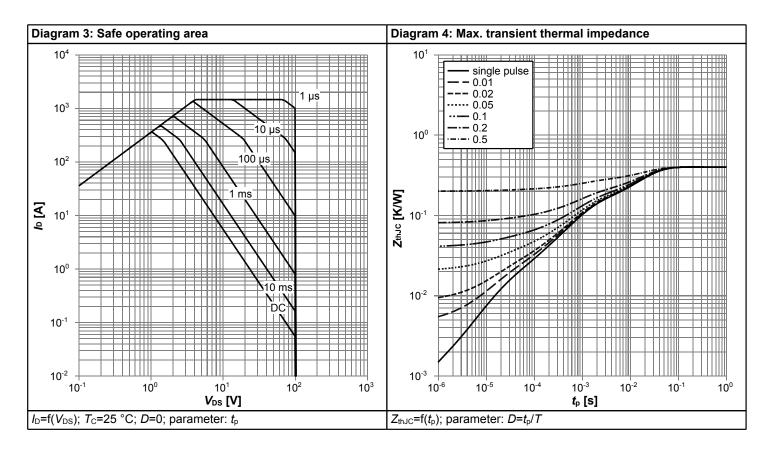
### Table 7 Reverse diode

Danamatan	Symbol		Values			Nata / Tank Oam dition
Parameter		Min.	Тур.	Max.	Unit	Note / Test Condition
Diode continuous forward current	Is	-	-	320	Α	<i>T</i> <sub>C</sub> =25 °C
Diode pulse current	I <sub>S,pulse</sub>	-	-	1460	Α	<i>T</i> <sub>C</sub> =25 °C
Diode forward voltage	V <sub>SD</sub>	-	0.88	1.0	V	V <sub>GS</sub> =0 V, I <sub>F</sub> =150 A, T <sub>j</sub> =25 °C
Reverse recovery time <sup>1)</sup>	t <sub>rr</sub>	-	103	206	ns	V <sub>R</sub> =50 V, I <sub>F</sub> =100 A, dI <sub>F</sub> /dt=100 A/μs
Reverse recovery charge <sup>1)</sup>	Qrr	-	316	632	nC	$V_R$ =50 V, $I_F$ =100 A, $di_F/dt$ =100 A/ $\mu$ s

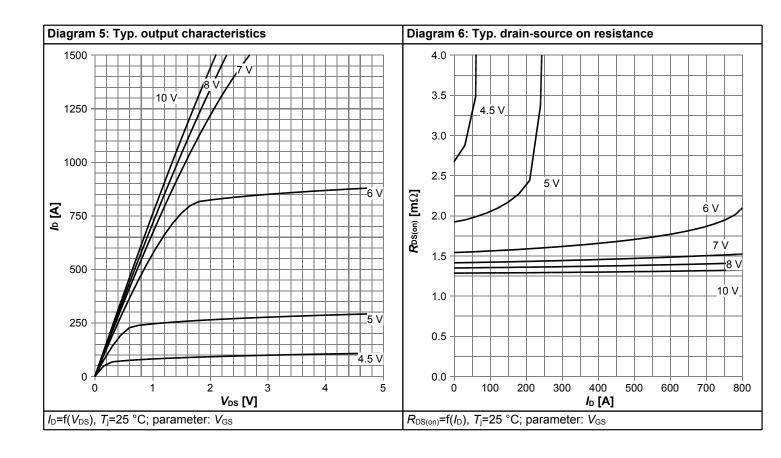


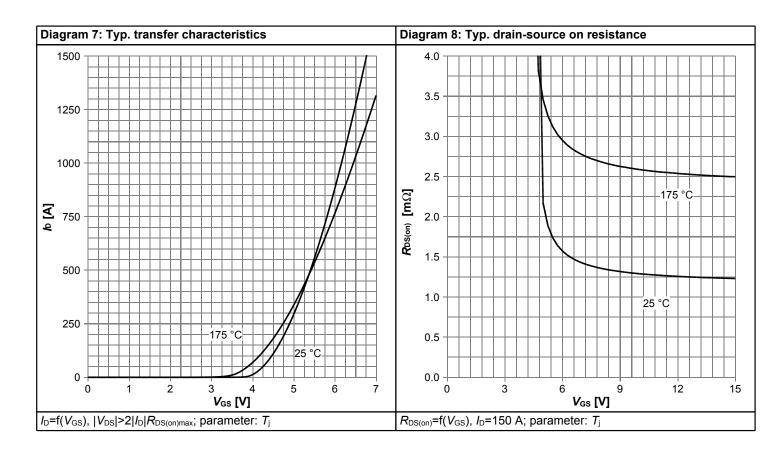
# 4 Electrical characteristics diagrams



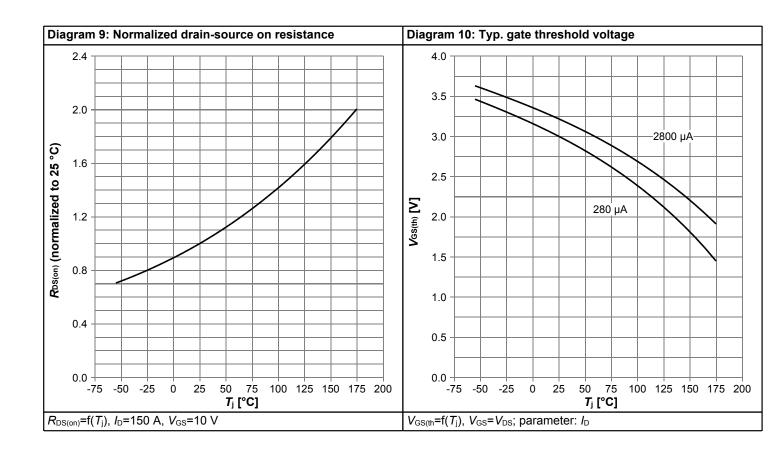


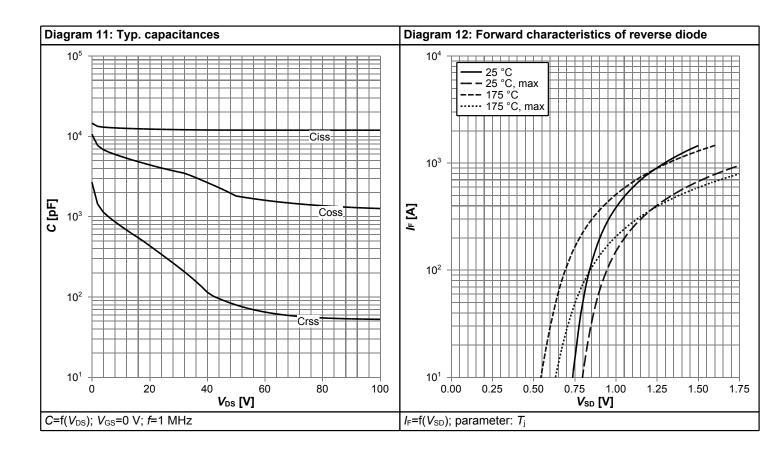




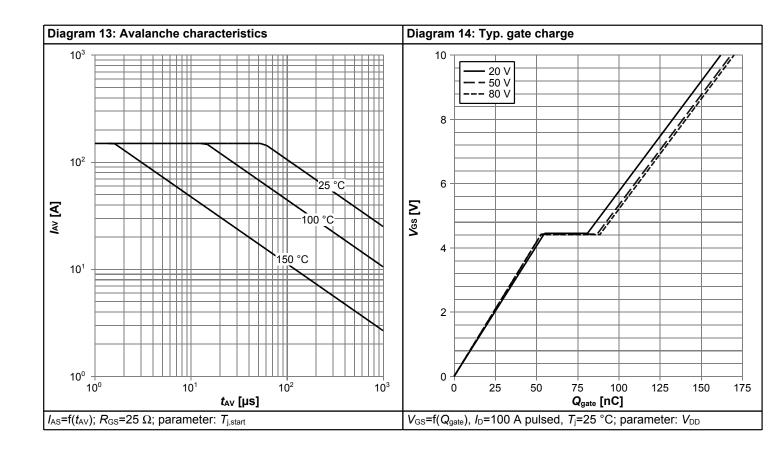


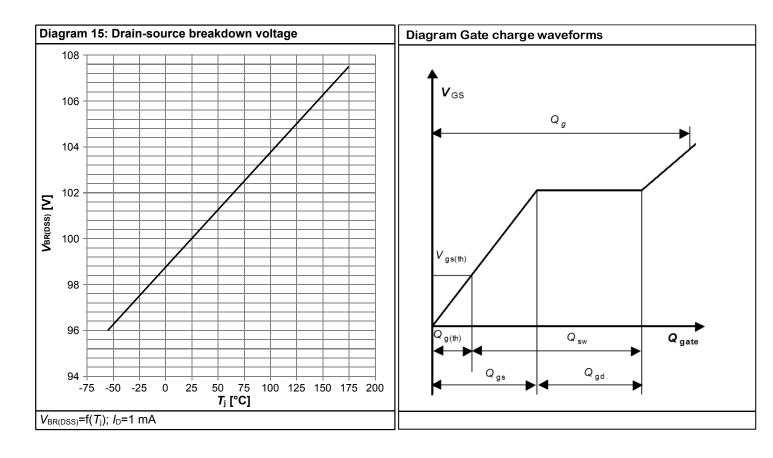






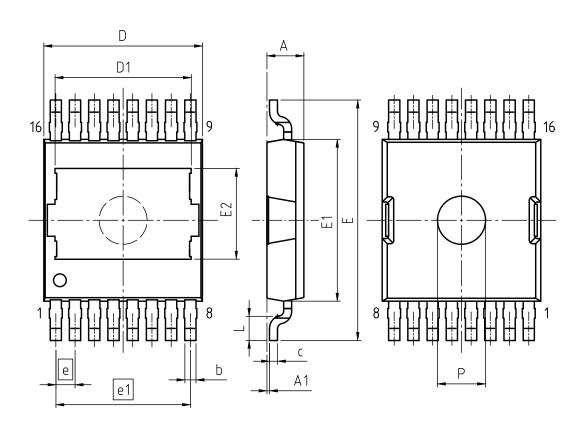








# 5 Package Outlines



PACKAGE - GROUP NUMBER:	PG-HDSC	P-16-U01
REVISION: 01	DATE:	18.12.2020
DIMENSIONS	MILLIM	ETERS
DIMENSIONS	MIN.	MAX.
Α	2.25	2.35
A1	0.01	0.16
b	0.60	0.80
С	0.40	0.60
D	9.70	10.10
D1	8.20	8.40
E	14.80	15.20
E1	10.00	10.30
E2	5.57	5.77
е	1.:	20
e1	8.	40
L	1.40	1.60
P	2.90	3.10

Figure 1 Outline PG-HDSOP-16, dimensions in mm



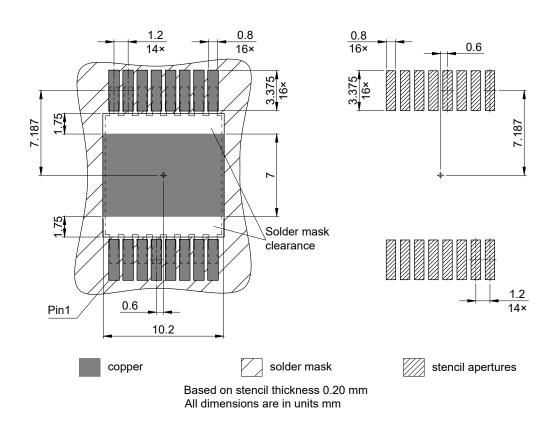
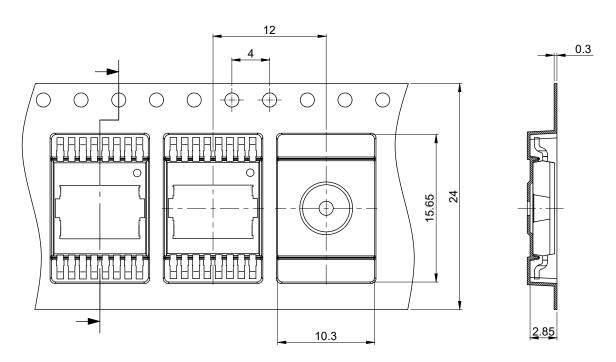


Figure 2 Outline Footprint (PG-HDSOP-16), dimensions in mm





All dimensions are in units mm

The drawing is in compliance with ISO 128-30, Projection Method 1 [

Figure 3 Outline Tape (PG-HDSOP-16), dimensions in mm

# OptiMOS<sup>TM</sup> 5 Power-Transistor, 100 V



#### **Revision History**

IPTC014N10NM5

Revision: 2022-05-24, Rev. 2.0

Previous Revision

Revision	Date	Subjects (major changes since last revision)			
2.0	2022-05-24	Release of final version			

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